



MJ N-Channel Enhancement Mode Power MOSFET

Description

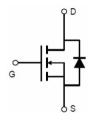
The MJ3020Q uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

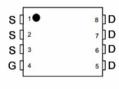
General Features

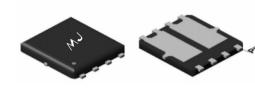
- ♦ High density cell design for ultra low Rdson
- ◆ Fully characterized Avalanche voltage and current
- ◆ Good stability and uniformity with high EAS
- ◆ Excellent package for good heat dissipation
- ◆ Special process technology for high ESD capability

Application

- ◆ Power switching application
- ◆ Hard Switched and High Frequency Circuits
- ◆ Uninterruptible Power Supply







Schematic diagram

Pin Assignment

Top View

Bottom View

100% UIS TESTED! 100% ΔVds TESTED!

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
MJ3020Q	MJ3020Q	DFN 3.3x3.3-8L	-	-	-

Absolute Maximum Ratings (Tc =25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	30	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	lo	20	А
Drain Current-Continuous(Tc =100°C)	ID(100°C)	14.1	А
Pulsed Drain Current	Ідм	80	А
Maximum Power Dissipation	Po	20	W
Single pulse avalanche energy (Note 5)	Eas	72	mJ
Derating factor		0.27	W/°C
Operating Junction and Storage Temperature Range	Тл ,Тѕтс	-55 To 150	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Case (Note 2)	RθJA	6.25	°C/W
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Electrical Characteristics (TA =25°Cunless otherwise noted)

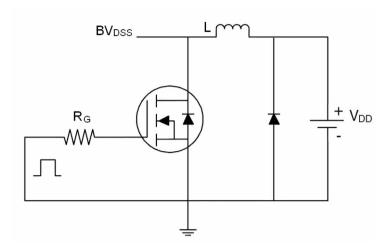
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	·					
Drain-Source Breakdown Voltage	BVDSS	V _{GS} =0V I _D =250µA	30	-	-	V
Zero Gate Voltage Drain Current	Ipss	V _{DS} =30V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	Igss	V _{DS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	'					
Gate Threshold Voltage	VGS(th)	V _{DS} =V _{GS} ,I _D =250μA	1.0	1.5	2.2	V
Drain-Source On-State Resistance		V _{GS} =10V, I _D =10A	-	6.8	8	mΩ
Drain-Source On-State Nesistance	Rds(on)	Vgs=4.5V, Ip=10A	-	8.8	12	mΩ
Forward Transconductance	g FS	V _{DS} =5V,I _D =10A	26	-	-	S
Dynamic Characteristics (Note 4)						ı
Input Capacitance	Clss		-	1000	-	PF
Output Capacitance	Coss	V _{DS} =15V,V _{GS} =0V, F=1.0MHz	-	180.8	***	PF
Reverse Transfer Capacitance	Crss	-	-	164.4	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	5	-	nS
Turn-on Rise Time	tr	V _{DD} =15V, R _L =0.75Ω V _{GS} =10V,R _G =3Ω	-	12	-	nS
Turn-Off Delay Time	td(off)		-	19	-	nS
Turn-Off Fall Time	tf		-	6	-	nS
Total Gate Charge	Qg		_	17	-	nC
Gate-Source Charge	Qgs	V _{DS} =15V,I _D =20A, V _{GS} =10V	-	2.8	-	nC
Gate-Drain Charge	Q _{gd}	-	-	3.9	-	nC
Drain-Source Diode Characteristics	l					l
Diode Forward Voltage (Note 3)	VsD	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	ls		_	-	20	А
Reverse Recovery Time	trr	TJ=25°C, IF=10A	-	19	-	nS
Reverse Recovery Charge	Qrr	di/dt=100A/µs (Note 3)	_	10	-	nC
Forward Turn-On Time	ton	Intrinsic turn-on time is n	ealiaible(ti	ırn-on is d	ominated h	 v S+ Г

Notes:

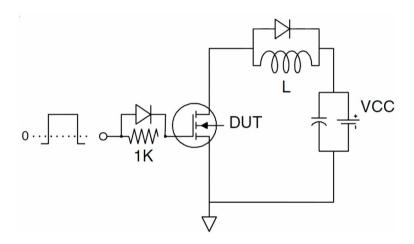
- $\textcircled{1} \ \ \mathsf{Repetitive} \ \ \mathsf{Rating:} \ \ \mathsf{Pulse} \ \ \mathsf{width} \ \ \mathsf{limited} \ \ \mathsf{by} \ \ \mathsf{maximum} \ \ \mathsf{junction} \ \ \mathsf{temperature}.$
- ② Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3 Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- $\ensuremath{\mathfrak{A}}$ Guaranteed by design, not subject to production



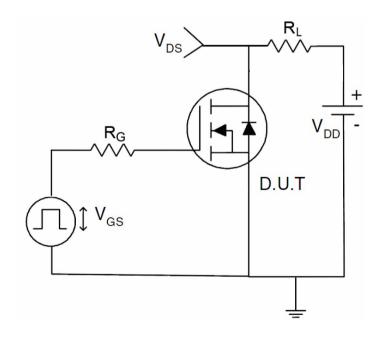




Eas test Circuit



Gate charge test Circuit



Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

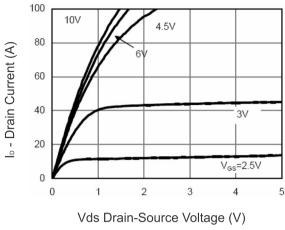
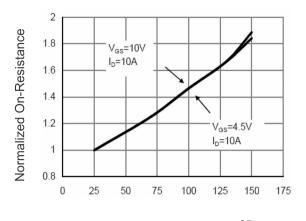


Figure 1 Output Characteristics



T_J -Junction Temperature(°C) Figure 4 Rdson-Junction Temperature

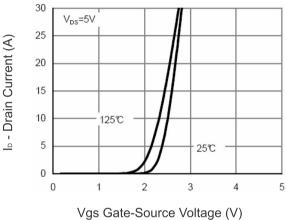


Figure 2 Transfer Characteristics

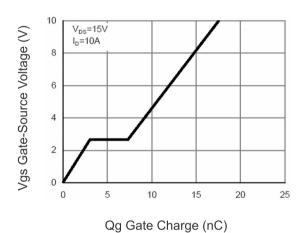


Figure 5 Gate Charge

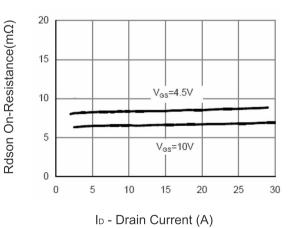


Figure 3 Rdson- Drain Current

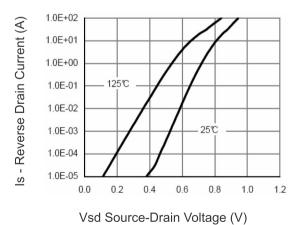


Figure 6 Source- Drain Diode Forward



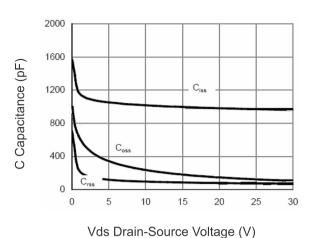
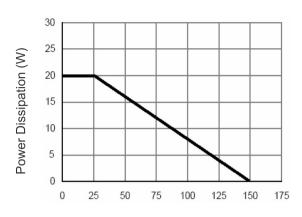


Figure 7 Capacitance vs Vds



T_J -Junction Temperature(°C) Figure 9 Power De-rating

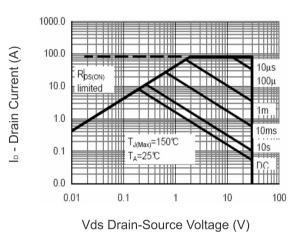
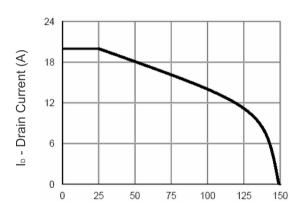
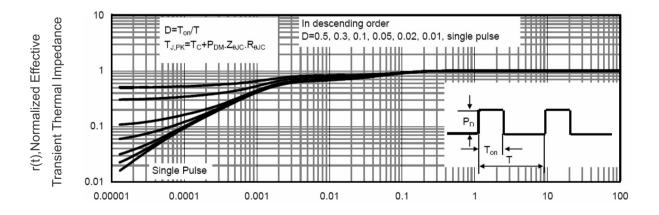


Figure 8 Safe Operation Area



T_J -Junction Temperature(°C) Figure 10 In Current De-rating



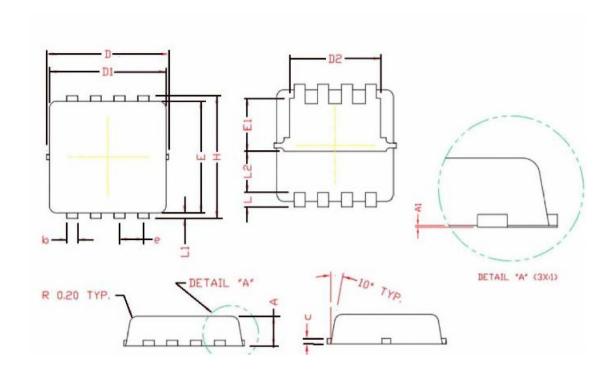
Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance





DFN3.3X3.3-8L Package Information



COMMON DIMENSIONS

(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
A	0.70	0.80	0.90	
A1	0.00	0.03	0.05	
b	0.24	0.30	0.35	
С	0.10	0.15	0.20	
D	3. 25	3. 32	3.40	
D1	3.05	3. 15	3.25	
D2	2.40	2.50	2.60	
E	3.00	3.10	3.20	
E1	1.35	1.45	1.55	
е	0.65 BSC.			
Н	3. 20	3.30	3.40	
L	0.30	0.40	0.50	
L1	0.10	0.15	0.20	
L2	1.13 REF.			





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